

# SFP9644-VB Datasheet

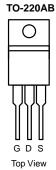
### **Power MOSFET**

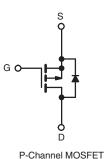
PRODUCT SUMMARY				
V <sub>DS</sub> (V)	- 250			
$R_{DS(on)}\left(\Omega\right)$	V <sub>GS</sub> = - 10 V	1.0		
Q <sub>g</sub> (Max.) (nC)	38			
Q <sub>gs</sub> (nC)	8.0			
Q <sub>gd</sub> (nC)	18			
Configuration	Single			

#### **FEATURES**

- Advanced Process Technology
- Dynamic dV/dt Rating
- 150 °C Operating Temperature
- Fast Switching
- P-Channel
- Fully Avalanche Rated
- Lead (Pb)-free Available







PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			$V_{DS}$	- 250	V	
Gate-Source Voltage			$V_{GS}$	± 20	V	
Continuous Drain Current	V <sub>GS</sub> at - 10 V	T <sub>C</sub> = 25 °C	1-	- 6.0	A	
		$T_C = 100 ^{\circ}C$	I <sub>D</sub>	- 4.0		
Pulsed Drain Current <sup>a</sup>			$I_{DM}$	- 16		
Linear Derating Factor				0.28	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	520	mJ	
Repetitive Avalanche Current <sup>a</sup>			I <sub>AR</sub>	- 4.1	Α	
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	3.5	mJ	
Maximum Power Dissipation	T <sub>C</sub> =	T <sub>C</sub> = 25 °C		85	W	
Peak Diode Recovery dV/dt <sup>c</sup>			dV/dt	- 5.0	V/ns	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C		
Soldering Recommendations (Peak Temperature)	for 1	10 s		300 <sup>d</sup>	7	
Mounting Torque	6 32 or N	6-32 or M3 screw		10	lbf ⋅ in	
	0-32 OF IV			1.1	N · m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Starting T<sub>J</sub> = 25 °C, L = 62 mH, R<sub>G</sub> = 25  $\Omega$ , I<sub>AS</sub> = 4.1 A (see fig. 12). c. I<sub>SD</sub>  $\leq$  4.1 A, dI/dt  $\leq$  640 A/ $\mu$ s, V<sub>DD</sub>  $\leq$  V<sub>DS</sub>, T<sub>J</sub>  $\leq$  150 °C. d. 1.6 mm from case.

<sup>\*</sup> Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	65	°C/W	
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	3.6	C/VV	

PARAMETER	SYMBOL	TES	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		- 250	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	Reference to 25 °C, I <sub>D</sub> = 1 mA		- 0.27	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$		-	- 4.0	V
Gate-Source Leakage	I <sub>GSS</sub>	,	V <sub>GS</sub> = ± 20 V		-	± 100	nA
Zara Onto Walleria D. C. C.		V <sub>DS</sub> =	V <sub>DS</sub> = - 250 V, V <sub>GS</sub> = 0 V		-	- 25	μΑ
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = - 200	V <sub>DS</sub> = - 200 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 150 °C		-	- 250	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = - 10 V	I <sub>D</sub> = - 2.5 A <sup>b</sup>	-	1.0	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> =	- 50 V, I <sub>D</sub> = - 4.1 A <sup>b</sup>	2.2	-	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>		V <sub>GS</sub> = 0 V,	-	680	-	
Output Capacitance	C <sub>oss</sub>	$V_{DS} = -25 V$ ,		-	170	-	
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1	.0 MHz, see fig. 5	-	40	-	pF
Drain to Sink Capacitance	С		f = 1.0 MHz	-	12	-	
Total Gate Charge	$Q_g$	V <sub>GS</sub> = - 10 V	I <sub>D</sub> = -4.1 A, V <sub>DS</sub> = -200 V, see fig. 6 and 13 <sup>b</sup>	ı	-	38	nC
Gate-Source Charge	$Q_{gs}$			1	-	8.0	
Gate-Drain Charge	$Q_{gd}$			-	-	18	
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD}$ = - 130 V, $I_{D}$ = - 4.1 A, $R_{G}$ = 12 $\Omega$ , $R_{D}$ = 31 $\Omega$ , see fig. 10 <sup>b</sup>		-	12	-	- ns
Rise Time	t <sub>r</sub>			-	23	-	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	34	-	
Fall Time	t <sub>f</sub>			-	21	-	
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	n1.1
Internal Source Inductance	L <sub>S</sub>			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	- 4.1	- A
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	- 16	
Body Diode Voltage	$V_{SD}$	$T_J = 25  ^{\circ}\text{C},  I_S = -4.1  \text{A},  V_{GS} = 0  V^b$		-	-	- 6.5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	$T_J = 25  ^{\circ}\text{C},  I_F = -4.1  \text{A},  \text{dl/dt} = -100  \text{A/} \mu \text{s}^{\text{b}}$		-	190	290	ns
Body Diode Reverse Recovery Charge	$Q_{rr}$			-	1.5	2.2	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S$ and $L_D$ )				L <sub>D</sub> )	

#### Notes

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- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width  $\leq$  300  $\mu s;$  duty cycle  $\leq$  2 %.



### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

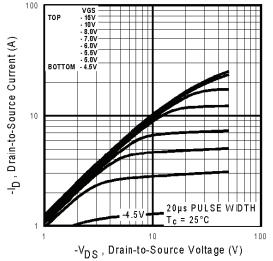


Fig. 1 - Typical Output Characteristics,  $T_C$  = 25  $^{\circ}C$ 

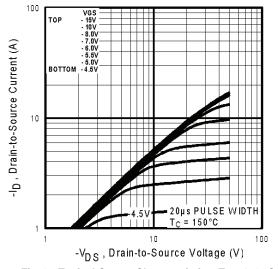


Fig. 2 - Typical Output Characteristics, T  $_{\text{C}}\text{=}$  150  $^{\circ}\text{C}$ 

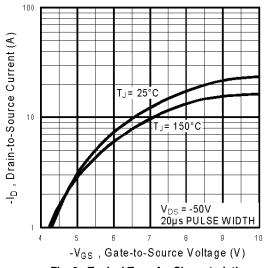


Fig. 3 - Typical Transfer Characteristics

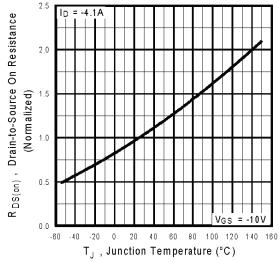


Fig. 4 - Normalized On-Resistance vs. Temperature



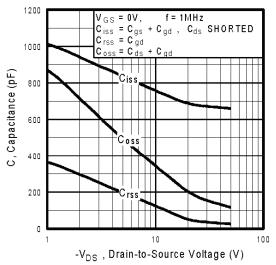


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

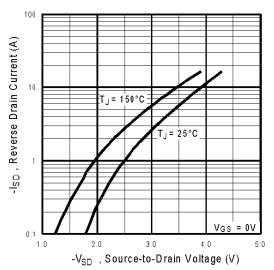


Fig. 7 - Typical Source-Drain Diode Forward Voltage

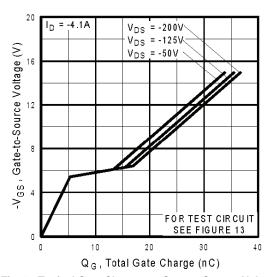


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

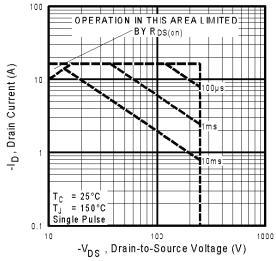


Fig. 8 - Maximum Safe Operating Area



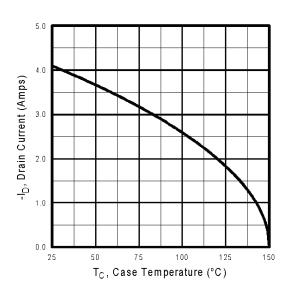


Fig. 9 - Maximum Drain Current vs. Case Temperature

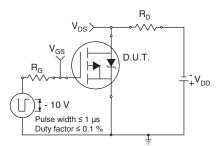


Fig. 10a - Switching Time Test Circuit

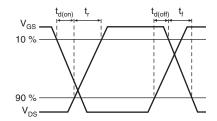


Fig. 10b - Switching Time Waveforms

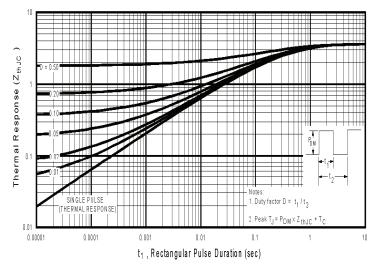


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

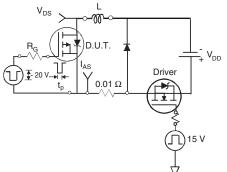


Fig. 12a - Unclamped Inductive Test Circuit

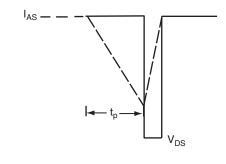


Fig. 12b - Unclamped Inductive Waveforms



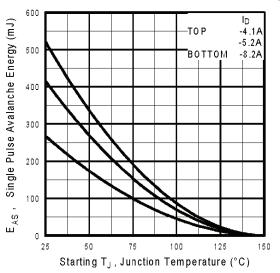


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

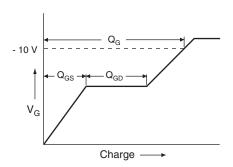


Fig. 13a - Basic Gate Charge Waveform

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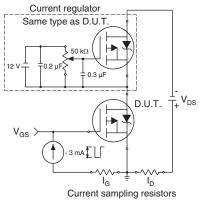
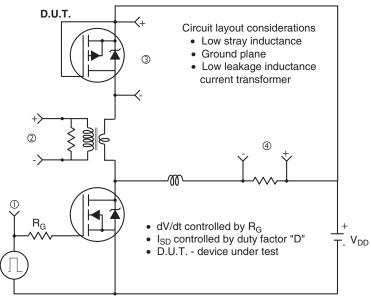


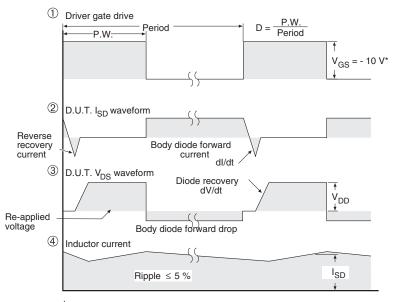
Fig. 13b - Gate Charge Test Circuit



## Peak Diode Recovery dV/dt Test Circuit



• Compliment N-Channel of D.U.T. for driver



\*  $V_{GS} = -5 \text{ V}$  for logic level and -3 V drive devices

Fig. 14 - For P-Channel



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